

Abstract of the Disclosure

An apparatus for optimizing actual woven fabrics on the basis of measured yarn data has at least one measuring device for measuring the yarn diameter, a structure input device for inputting and freely changing definable structures, a device for controlling the measuring device and for evaluation, and a display device. The actual fabric is computed and represented on the basis of the measured yarn diameters and the freely definable structure. The defined structure of the fabric can be changed making it possible to adapt and optimize the actual fabric to the measured individual yarn diameters.

Substitute Specification
US Patent Application 09/423,179
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Attorney Docket (K) 53 885

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